

Notice of References Cited

Application/Control No.

10/655,838

Applicant(s)/Patent Under
Reexamination
EPSTEIN ET AL.

Examiner

Natalie Lennox

Art Unit

2626

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0087316	07-2002	Lee et al.	704/257
*	B	US-2003/0216905	11-2003	Chelba et al.	704/9
*	C	US-2005/0055199	03-2005	Ryzchachkin et al.	704/004
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Adwait Ratnaparkhi, Learning to Parse Natural Language with Maximum Entropy Models, Machine Learning, v.34 n. 1-3, p. 151-175, Feb. 1999
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.